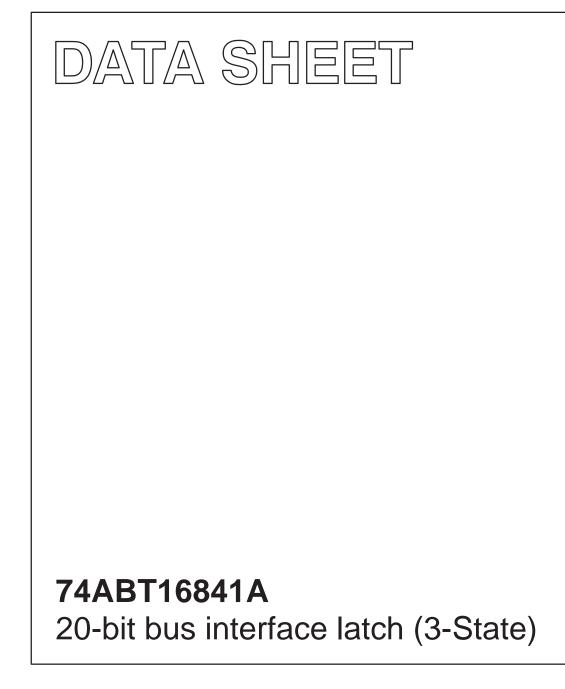
INTEGRATED CIRCUITS



Product data Replaces data sheet 74ABT16841A/74ABTH16841A of 2002 Dec 17 2004 Feb 02



74ABT16841A

FEATURES

- High speed parallel latches
- Live insertion/extraction permitted
- Extra data width for wide address/data paths or buses carrying parity
- Power-up 3-State
- Power-up reset
- Ideal where high speed, light loading, or increased fan-in are required with MOS microprocessors
- Output capability: +64 mA / -32 mA
- Latch-up protection exceeds 500 mA per Jedec Std 17
- ESD protection exceeds 2000 V per MIL STD 883 Method 3015 and 200 V per Machine Model

DESCRIPTION

The 74ABT16841A Bus interface latch is designed to provide extra data width for wider data/address paths of buses carrying parity.

The 74ABT16841A consists of two sets of ten D-type latches with 3-State outputs. The flip-flops appear transparent to the data when Latch Enable (nLE) is HIGH. This allows asynchronous operation, as the output transition follows the data in transition. On the nLE HIGH-to-LOW transition, the data that meets the set-up and hold time is latched.

Data appears on the bus when the Output Enable ($n\overline{OE}$) is LOW. When $n\overline{OE}$ is HIGH the output is in the high-impedance state.

QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS T _{amb} = 25 °C; GND = 0 V	TYPICAL	UNIT
t _{PLH} t _{PHL}	Propagation delay nDx to nQx	$C_{L} = 50 \text{ pF}; V_{CC} = 5 \text{ V}$	3.1 2.2	ns
C _{IN}	Input capacitance	$V_{I} = 0 V \text{ or } V_{CC}$	4	pF
C _{OUT}	Output capacitance	$V_O = 0 V \text{ or } V_{CC}$; 3-State	7	pF
I _{CCZ}	Quiaccent cumply current	Outputs disabled; V_{CC} = 5.5 V	500	μΑ
ICCL	Quiescent supply current	Outputs LOW; $V_{CC} = 5.5 V$	10	mA

ORDERING INFORMATION

 $T_{amb} = -40 \circ C$ to $+85 \circ C$

Type number	Package	Package				
	Name	Description	Version			
74ABT16841ADL	SSOP56	plastic shrink small outline package; 56 leads; body width 7.5 mm	SOT371-1			
74ABT16841ADGG	TSSOP56	plastic thin shrink small outline package; 56 leads; body width 6.1 mm	SOT364-1			

PIN DESCRIPTION

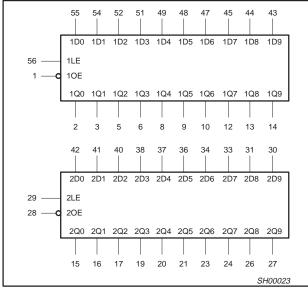
PIN NUMBER	SYMBOL	FUNCTION
55, 54, 52, 51, 49, 48, 47, 45, 44, 43 42, 41, 40, 38, 37, 36, 34, 33, 31, 30	1D0 – 1D9 2D0 – 2D9	Data inputs
2, 3, 5, 6, 8, 9, 10, 12, 13, 14 15, 16, 17, 19, 20, 21, 23, 24, 26, 27	1Q0 – 1Q9 2Q0 – 2Q9	Data outputs
1, 28	10E, 20E	Output enable inputs (active-LOW)
56, 29	1LE, 2LE	Latch enable inputs (active rising edge)
4, 11, 18, 25, 32, 39, 46, 53	GND	Ground (0 V)
7, 22, 35, 50	V _{CC}	Positive supply voltage

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PIN CONFIGURATION

10E [56 1LE
1Q0 [2	55 1D0
1Q1 [3	54 1D1
GND [4	53 GND
1Q2 [5	52 1D2
1Q3 [6	51 1D3
V _{CC} [7	50 VCC
1Q4 [8	49 1D4
1Q5 [9	48 1D5
1Q6 [10	47 1D6
GND [11	46 GND
1Q7 [12	45 1D7
1Q8 [13	44 1D8
1Q9 [14	43 1D9
2Q0 [15	42 2D0
2Q1 [16	41 2D1
2Q2 [17	40 2D2
GND [18	39 GND
2Q3 [19	38 2D3
2Q4 [20	37 2D4
2Q5 [21	36 2D5
Vcc [22	35 VCC
2Q6 [23	34 2D6
2Q7 [24	33 2D7
GND	25	32 GND
2Q8	26	31 2D8
2Q9 [27	30 2D9
20E	28	29 2LE
	L	I
		SA00076

LOGIC SYMBOL



LOGIC SYMBOL (IEEE/IEC)

1 0E	1	EN2
1LE	56	C1
2 0E	28	EN4
2LE	29	C3
	55	
1D0	54	12 2 1
1D1	52	
1D2	51	
1D3	49	
1D4	49	
1D5		<u> </u>
1D6	47	<u> </u>
1D7	45	<u> </u>
1D8	44	<u>13</u> 1Q8
1D9	43	<u>14</u> 1Q9
2D0	42	3D 4 V 15 2Q0
2D1	41	<u> </u>
2D2	40	<u> </u>
2D3	38	<u>19</u> 2Q3
2D4	37	
2D5	36	212Q5
2D6	34	232Q6
2D7	33	
2D8	31	<u>26</u> 2Q8
2D9	30	272Q9
		SH00081

FUNCTION TABLE

	INPUTS	6	OUTPUTS	OPERATING MODE		
nOE	nLE	nDx	nQ0 – nQ9	OPERATING MODE		
L	H H	L H	L H	Transparent		
L	$\rightarrow \rightarrow$	l h	L H	Latched		
н	Х	Х	Z	High impedance		
L	L	Х	NC	Hold		

H = HIGH voltage level

h = HIGH voltage level one set-up time prior to the HIGH-to-LOW LE transition

1

 LOW voltage level
LOW voltage level one set-up time prior to the HIGH-to-LOW L LE transition

 \downarrow = HIGH-to-LOW LE transition

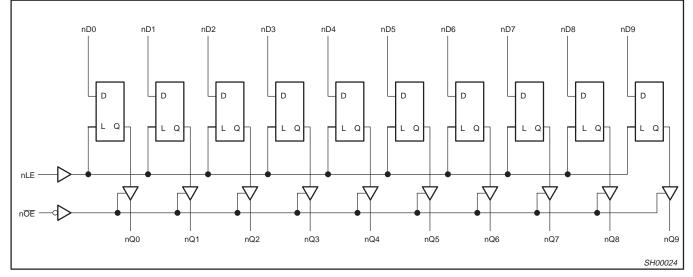
NC= No change

X = Don't care Z = High impedance "off" state

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Product data

LOGIC DIAGRAM



ABSOLUTE MAXIMUM RATINGS^{1, 2}

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V _{CC}	DC supply voltage		-0.5 to +7.0	V
I _{IK}	DC input diode current	V ₁ < 0 V	-18	mA
VI	DC input voltage ³		-1.2 to +7.0	V
I _{OK}	DC output diode current	V _O < 0 V	-50	mA
V _{OUT}	DC output voltage ³	Output in Off or HIGH state	-0.5 to +5.5	V
		Output in LOW state	128	
lout	DC output current	Output in HIGH state	-64	— mA
T _{stg}	Storage temperature range		-65 to 150	°C

NOTES:

 Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

2. The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150 °C.

3. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIM	UNIT	
STWBOL	PARAMETER	Min	Max	UNIT
V _{CC}	DC supply voltage	4.5	5.5	V
VI	Input voltage	0	V _{CC}	V
V _{IH}	HIGH-level input voltage	2.0	-	V
V _{IL}	LOW-level Input voltage	-	0.8	V
I _{ОН}	HIGH-level output current	-	-32	mA
I _{OL}	LOW-level output current	-	64	mA
Δt/Δv	Input transition rise or fall rate	0	5	ns/V
T _{amb}	Operating free-air temperature range	-40	+85	°C

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DC ELECTRICAL CHARACTERISTICS

			LIMITS					
SYMBOL	PARAMETER	TEST CONDITIONS	T _{amb} = +25 ℃			T _{amb} = −40 °C to +85 °C		
			Min	Тур	Max	Min	Max	
V _{IK}	Input clamp voltage	$V_{CC} = 4.5 \text{ V}; \text{ I}_{IK} = -18 \text{ mA}$	-	-0.9	-1.2	-	-1.2	V
		V_{CC} = 4.5 V; I_{OH} = –3 mA; V_{I} = V_{IL} or V_{IH}	2.5	2.9	-	2.5	-	V
V _{OH}	HIGH-level output voltage	V_{CC} = 5.0 V; I_{OH} = -3 mA; V_I = V_{IL} or V_{IH}	3.0	3.4	-	3.0	-	V
		V_{CC} = 4.5 V; I_{OH} = -32 mA; V_I = V_{IL} or V_{IH}	2.0	2.4	-	2.0	-	V
V _{OL}	LOW-level output voltage	V_{CC} = 4.5 V; I_{OL} = 64 mA; V_I = V_{IL} or V_{IH}	-	0.42	0.55	-	0.55	V
V _{RST}	Power-up output voltage ³	V_{CC} = 5.5 V; I _O = 1 mA; V _I = GND or V _{CC}	-	0.13	0.55	-	0.55	V
I _I	Input leakage current	V_{CC} = 5.5 V; V_{I} = V_{CC} or GND	-	±0.01	±1	-	±1.0	μΑ
I _{OFF}	Power-off leakage current	V_{CC} = 0.0 V; V_O or V_I \leq 4.5 V	-	±5.0	±100	-	±100	μΑ
I _{PU/PD}	Power-up/down 3-State output current ⁴	V_{CC} = 2.1 V; V _O = 0.5 V; V _I = GND or V _{CC} ; V _{OE} = Don't care	-	±5.0	±50	-	±50	μA
I _{OZH}	3-State output High current	V_{CC} = 5.5 V; V_{O} = 2.7 V; V_{I} = V_{IL} or V_{IH}	-	5.0	10	-	10	μA
I _{OZL}	3-State output Low current	V_{CC} = 5.5 V; V_{O} = 0.5 V; V_{I} = V_{IL} or V_{IH}	-	-5.0	-10	-	-10	μΑ
I _{CEX}	Output High leakage current	V_{CC} = 5.5 V; V_{O} = 5.5 V; V_{I} = GND or V_{CC}	-	5.0	50	-	50	μA
Ι _Ο	Output current ¹	$V_{CC} = 5.5 \text{ V}; V_{O} = 2.5 \text{ V}$	-50	-70	-180	-50	-180	mA
I _{CCH}		V_{CC} = 5.5 V; Outputs High, V_{I} = GND or V_{CC}	-	0.5	1	-	1	mA
I _{CCL}	Quiescent supply current	V_{CC} = 5.5 V; Outputs Low, V_I = GND or V_{CC}	-	10	19	-	19	mA
I _{CCZ}		V_{CC} = 5.5 V; Outputs 3-State; V_I = GND or V_{CC}	-	0.5	1	-	1	mA
ΔI_{CC}	Additional supply current per input pin ²	V_{CC} = 5.5 V; one input at 3.4 V, other inputs at V_{CC} or GND	_	0.2	1	_	1	mA

NOTES:

1. Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

This is the increase in supply current for each input at 3.4 V.
For valid test results, data must not be loaded into the flip-flops (or latches) after applying the power.

4. This parameter is valid for any V_{CC} between 0 V and 2.1 V with a transition time of up to 10 msec. From V_{CC} = 2.1 V to V_{CC} = 5 V \pm 10% a transition time of up to 100 µsec is permitted. 5. Unused pins at V_{CC} or GND.

AC CHARACTERISTICS GND = 0 V, t_R = t_F = 2.5 ns, C_L = 50 pF, R_L = 500 Ω

					LIMI	TS		
SYMBOL	PARAMETER	WAVEFORM	T _a	_{amb} = +25 / _{CC} = +5.0	°C V	$\begin{array}{c} T_{amb} = -40 \\ V_{CC} = +5. \end{array}$	°C to +85 °C 0 V ±0.5 V	UNIT
			MIN	ТҮР	MAX	MIN	MAX	
t _{PLH} t _{PHL}	Propagation delay nDx to nQx	2	1.1 1.5	3.1 2.2	4.1 3.1	1.1 1.5	4.9 3.6	ns
t _{PLH} t _{PHL}	Propagation delay nLE to nQx	1	1.5 1.0	2.5 2.1	3.3 2.8	1.5 1.0	3.7 3.1	ns
t _{PZH} t _{PZL}	Output enable time to HIGH and LOW level	4 5	1.2 1.2	2.4 2.2	3.2 2.9	1.2 1.2	4.0 3.6	ns
t _{PHZ} t _{PLZ}	Output disable time from HIGH and LOW level	4 5	1.8 1.5	3.0 2.5	4.0 3.2	1.8 1.5	4.9 3.7	ns

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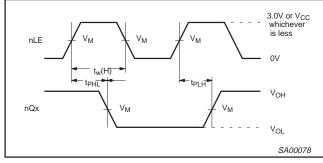
AC SET-UP REQUIREMENTS

GND = 0 V, t_{R} = t_{F} = 2.5 ns, C_{L} = 50 pF, R_{L} = 500 Ω

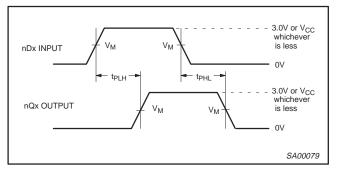
				LI	MITS		
SYMBOL	PARAMETER	WAVEFORM	T _{amb} = +25 °C V _{CC} = +5.0 V				UNIT
			Min	Тур	Min	Max	
t _s (H) t _s (L)	Set-up time, HIGH or LOW nDx to nLE	3	2.0 1.0	1.0 0.4	2.0 1.0		ns
t _h (H) t _h (L)	Hold time, HIGH or LOW nDx to nLE	3	2.0 2.0	-0.3 -0.7	2.0 2.0		ns
t _w (H)	nLE pulse width HIGH	1	2.9	1.9	2.9	-	ns

AC WAVEFORMS

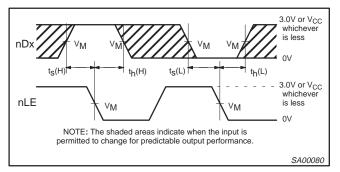
 V_{M} = 1.5 V, V_{IN} = GND to 3.0 V



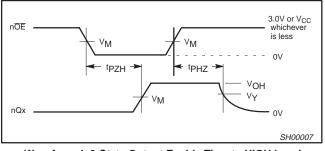
Waveform 1. Propagation Delay, Latch Enable Input to Output, and Enable Pulse Width



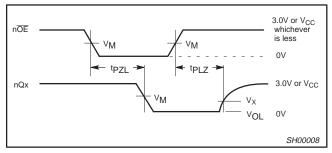
Waveform 2. Propagation Delay for Data to Outputs



Waveform 3. Data Set-up and Hold Times



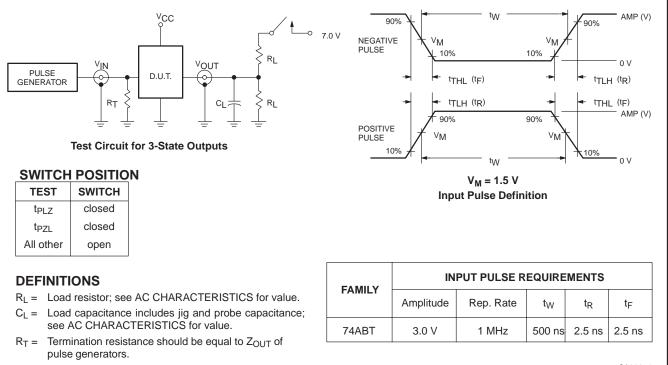
Waveform 4. 3-State Output Enable Time to HIGH Level and Output Disable Time from HIGH Level



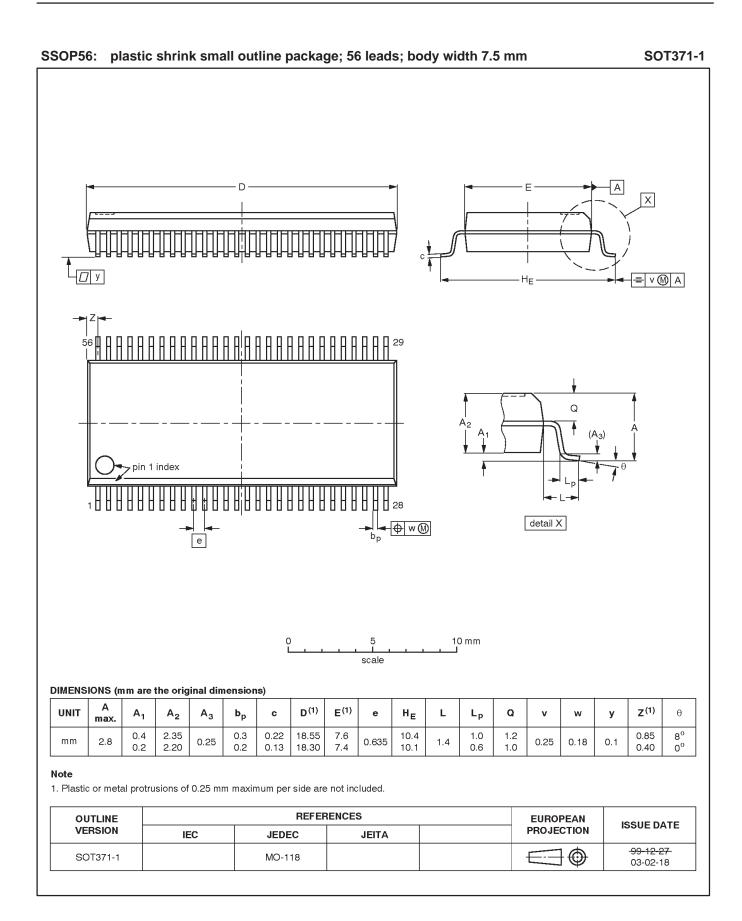
Waveform 5. 3-State Output Enable Time to LOW Level and Output Disable Time from LOW Level

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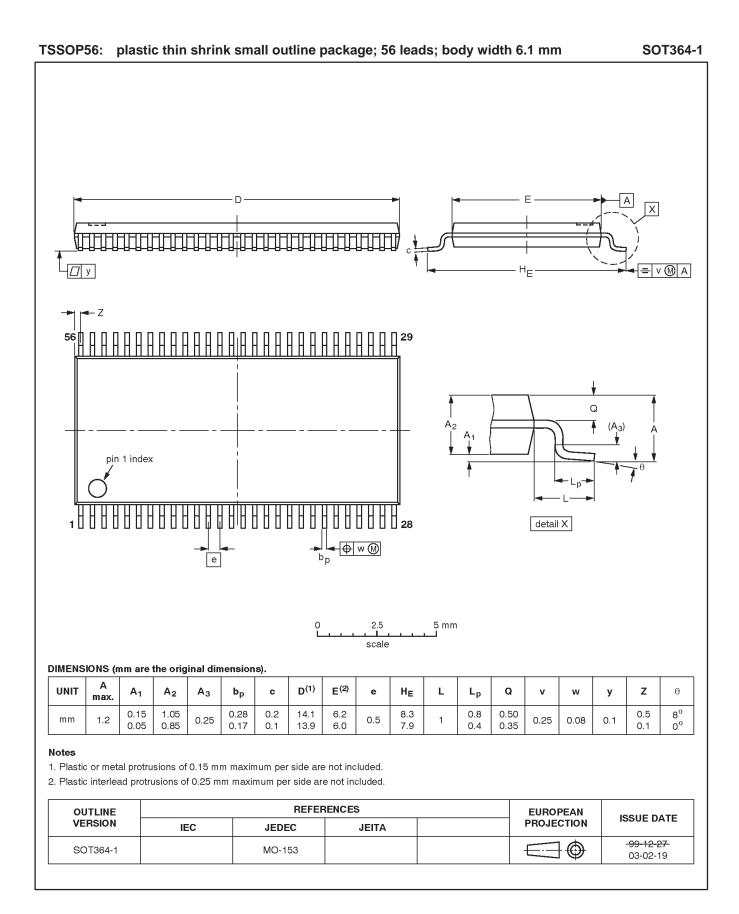
TEST CIRCUIT AND WAVEFORM



74ABT16841A



74ABT16841A



74ABT16841A

REVISION HISTORY

Rev	Date	Description
_3	20040202	Product data (9397 750 12821); 853-1797 ECN 01–A15433 of 27 January 2004. Replaces data sheet 74ABT_H16841A_2 of 2002 Dec 17 (9397 750 10845). Modifications: • Delete all references to 74ABTH16841A (product discontinued).
_2	20021217	Product data (9397 750 10845); ECN 853-1797 29296 of 12 December 2002. Supersedes data of 27 February 1998 (9397 750 03506).
_1	19980227	Product specification (9397 750 03506). ECN 853-1797 19025 of 27 February 1998.

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Data sheet status

Level	Data sheet status ^[1]	Product status ^{[2] [3]}	Definitions
I	Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
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[3] For data sheets describing multiple type numbers, the highest-level product status determines the data sheet status.

Definitions

Short-form specification — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 60134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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